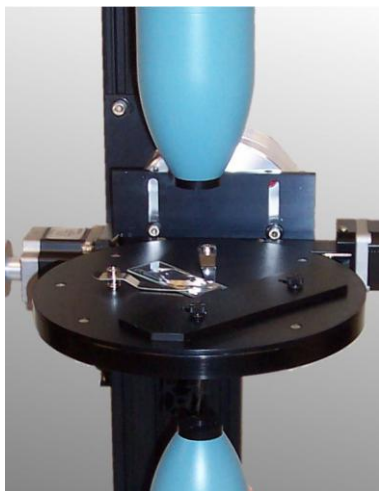


AxoScan MMSP with OPMF Fixture

Mueller Matrix Spectro-Polarimeter with Out-of-Plane Measurement Fixture

The AxoScan Mueller Matrix Spectro-Polarimeter is the most advanced polarization measurement system available. The system can measure every possible polarization property of a sample, including:

- Retardance magnitude and orientation
 - R0, Rth, and β
- Optical rotation / Circular retardance
- Polarizer transmission axis orientation and polarizer efficiency
- Circular dichroism
- Percent transmittance
- Depolarizing effects
- Complete Mueller matrix



On the OPMF-2, the sample tilts by +/- 75°, with rotation to any angle (0° to 360°)



The AxoScan OPMF-1 fixture tilts the sample +/- 55°, with rotation to any angle (0° to 360°)

Key Features

- High-speed measurements. The complete Mueller matrix can be acquired in 30 milliseconds
- Includes a Xe arc-lamp monochromator for spectral measurements between 400 and 800 nm.
- The AxoView software provides wide range of features
 - Measuring polarization spectra
 - Determining out-of-plane retardance, and refractive index differences
 - Characterizing the field-of-view properties of polarization elements.
- Two options for the out-of-plane measurement fixture:
 - 1) OPMF-1 tilts +/- 55°, with rotation 0° to 360°
 - 2) OPMF-2 tilts +/- 75°, with rotation 0° to 360°
- Optional Multi-Layer Software Package to determine the optical properties of individual layers of multi-layer samples
- Optional LCDView software to simultaneously measure cell gap, rubbing direction, twist, top pre-tilt, and bottom pre-tilt of liquid crystal samples.



光技術をサポートする

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